## Supporting Information -Non-stoichiometry in the Zintl phase $Yb_{1-\delta}Zn_2Sb_2$ as a route to thermoelectric optimization

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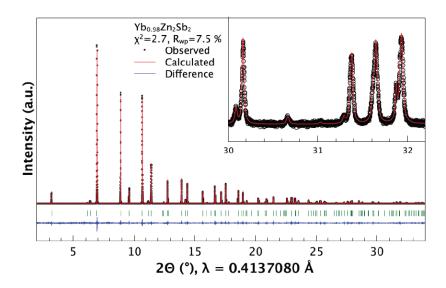


Figure S 1: Synchrotron diffraction data of nominal Yb<sub>0.98</sub>Zn<sub>2</sub>Sb<sub>2</sub>, including profile fit, profile difference and profile residuals ( $\chi^2$  and  $R_{wp}$ ) of the corresponding Rietveld refinement. The inset shows the goodness-of-fit at high angles.

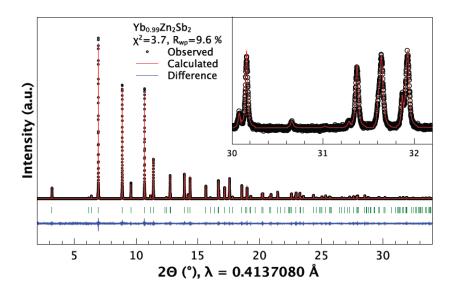


Figure S 2: Synchrotron diffraction data of nominal Yb<sub>0.99</sub>Zn<sub>2</sub>Sb<sub>2</sub>, including profile fit, profile difference and profile residuals ( $\chi^2$  and  $R_{wp}$ ) of the corresponding Rietveld refinement. The inset shows the goodness-of-fit at high angles.

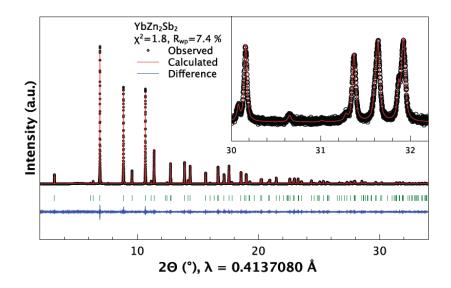


Figure S 3: Synchrotron diffraction data of nominal Yb<sub>1.00</sub>Zn<sub>2</sub>Sb<sub>2</sub>, including profile fit, profile difference and profile residuals ( $\chi^2$  and R<sub>wp</sub>) of the corresponding Rietveld refinement. The inset shows the goodness-of-fit at high angles.

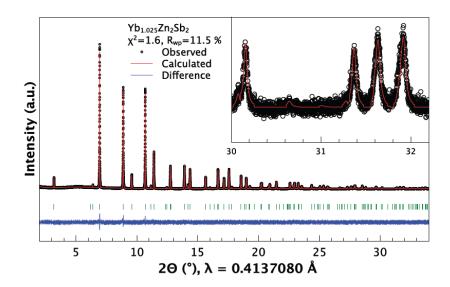


Figure S 4: Synchrotron diffraction data of nominal Yb<sub>1.025</sub>Zn<sub>2</sub>Sb<sub>2</sub>, including profile fit, profile difference and profile residuals ( $\chi^2$  and  $R_{wp}$ ) of the corresponding Rietveld refinement. The inset shows the goodness-of-fit at high angles.

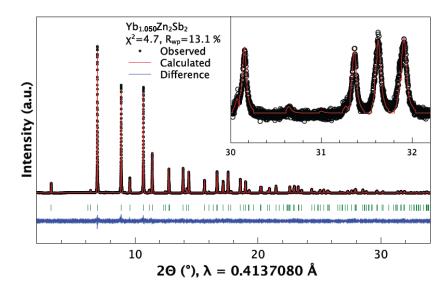


Figure S 5: Representative synchrotron diffraction data of Yb<sub>1.05</sub>Zn<sub>2</sub>Sb<sub>2</sub>, including profile fit, profile difference and profile residuals ( $\chi^2$  and  $R_{wp}$ ) of the corresponding Rietveld refinement. The inset shows the goodness-of-fit at high angles.

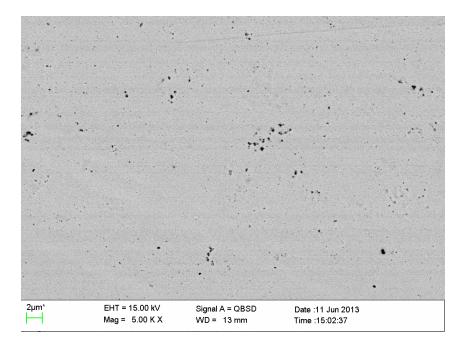


Figure S 6: Back-scattered SEM image of sample with x = 0.98. The black spots were identified as pores.

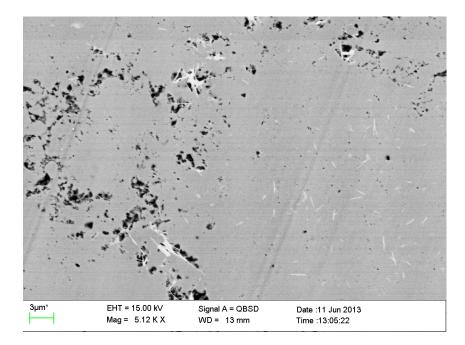


Figure S 7: Back-scattered SEM image of sample with x = 1.05. The black spots were identified as pores and white needles are a Yb-rich secondary phase.